

**Search Notes**

Application/Control No.

10/803,777

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under  
Reexamination

ENDO ET AL.

Art Unit

1745

**SEARCHED**

Class	Subclass	Date	Examiner
429	121	7/17/2007	DWY
429	127	7/17/2007	DWY
429	137	7/17/2007	DWY
429	185	7/17/2007	DWY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/17/2007	DWY